JC03 Rec'd PCT/PT0 1 4 NOV 2009

PATENT 8038-1062

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Takayuki SHIMAMUNE et al.

Application No. 10/527,801

(PCT/JP/03/11656)

Conf. 2298

PCT/DO/EO

Filed March 14, 2005

PROCESS FOR PRODUCING HIGH-PURITY SILICON AND APPARATUS

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 November 14, 2005

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying document, a copy of which is attached to this statement, is made of record on the enclosed Form PTO-1449.

A concise explanation of the relevance of this item is that this reference (JP 2003-342016) was cited in the erroneously corresponding International application but identified in the search report as 2003-242016.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION			Attorney Docket No.: 8038-1062		Application No.: 10/527,801		
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^{*} Abstract provided for the Examiner's convenience